

Search Notes



Application/Control No.

10/691,133

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375	229	1/11/06	CLS
↑	231	↑	↑
	232		
	233		
↓	234	↓	↓
375	350	1/11/06	CLS
375	295	1/11/06	CLS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
2 As I	1/11/06	CLS